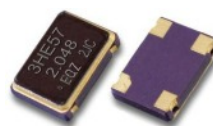


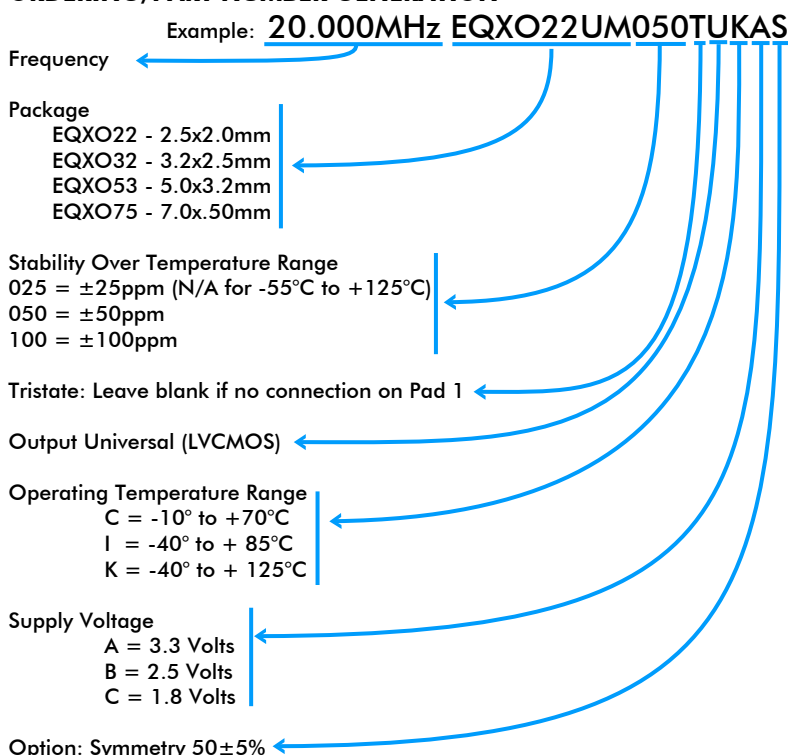
FEATURES

- Femto second integrated phase jitter 150fs typical (12kHz to 20MHz)
- Superior phase noise performance: -155dBc/Hz at 10kHz and -160dBc at 100kHz offset
- Wide operating temperature available to -40° to +125°C
- Military screened if required


SPECIFICATION

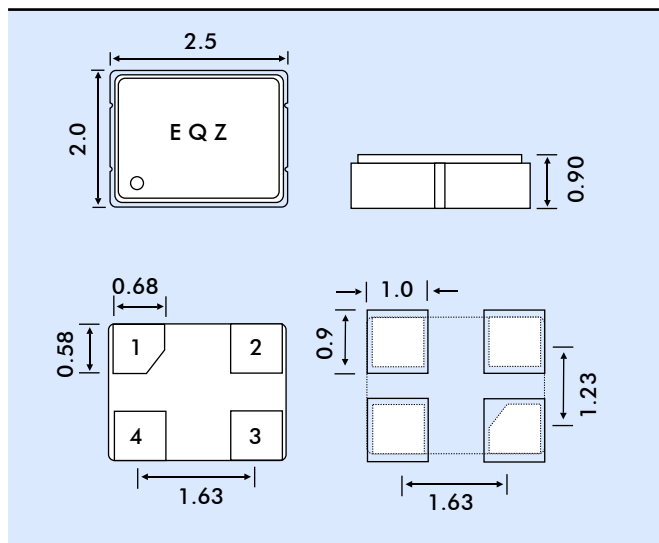
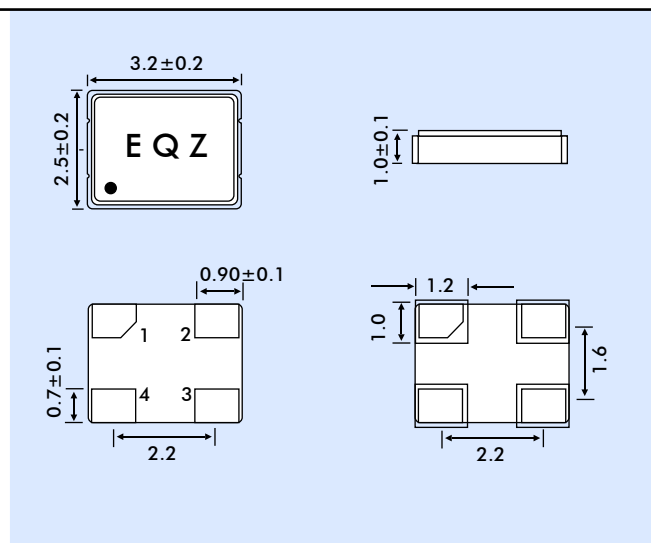
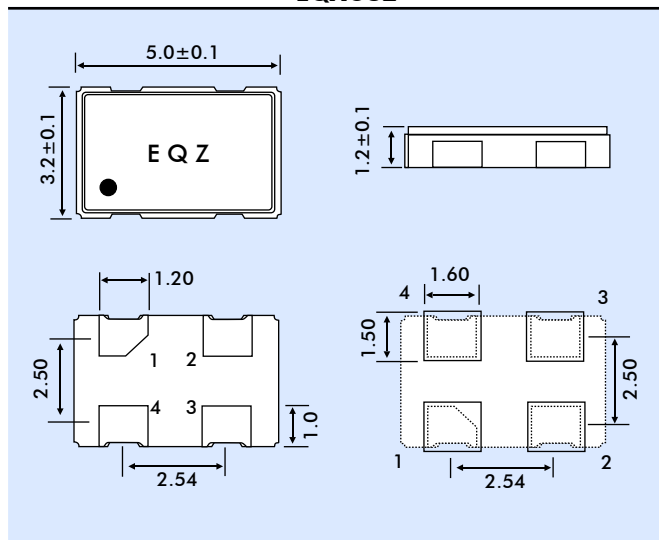
Model Number	EQXO-UM Series		
Frequency Range	2.000MHz to 50.000MHz		
Output Logic	LVCMOS		
Supply Voltage V _{DD}	1.8 V _{DD} ±10%	+2.5 V _{DD} ±10%	+3.3 V _{DD} ±10%
Logic High "1" (90% of V _{DD} minimum)	1.62V	2.25V	2.97V
Logic Low "0" (10% of V _{DD} maximum)	0.18V	0.25V	0.33V
Current Consumption	1.25~19.99MHz	2.0mA (max)	3.0mA (max)
	20~50.00MHz	4.0mA (max)	5.0mA (max)
Rise Time (Tr) / Fall Time (Tf)	10ns (max) measured 10% ~ 90% waveform		
Load	15pF		
Start-up Time	5ms (max)		
Duty Cycle	Standard: 50%±10% ; Option 50% ±5% (Add "S" after the part number for this option)		
Tristate Function	Tristate function on Pad 1 is standard for EQXO-UM series oscillators 70% of V _{DD} (min) Enable Output 30% of V _{DD} (max) Disable Output		
Phase Jitter (RMS) [26MHz, 3.3V]	150 fs typical (12kHz to 20MHz integrated)		

SSB Phase Noise [25MHz, 3.3V]	Offset	10Hz	100Hz	1kHz	10kHz	100kHz	1MHz	5MHz
	dBc/Hz (typical)	-94	-127	-142	-156	-161	-163	-163
Storage Temperature	-65° to +150°C							
Ageing at 25°C	±2ppm maximum for first year							
Solder Profile	260°C max.							

ORDERING/PART NUMBER GENERATION

Optional Screening

Screening in accordance with MIL-O-55310C Class B.
All devices are 100% tested to the following conditions:

Stabilisation Bake:	Vacuum storage at 150°C for 24hrs
Temperature Cycling:	-55°C to +125°C for 10 cycles
Constant Acceleration:	49000m/s ² for 1 minute in Y1 plane
Seal:	Fine leak to not exceed 1x10 ⁻⁸ mB litres of helium leakage & Gross Leak Test
Dynamic Burn-in:	125°C for 168hrs
Electrical Test:	Frequency, output waveform, output voltage/power, input current/power

EQXO22**EQXO32****EQXO52****EQXO75**